Please **ADD** the claims 19-22 as follows:

19. (NEW) The characteristic value identification method as claimed in claim 2, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

20. (NEW) The characteristic value identification method as claimed in claim 3, wherein the third process includes:

a first step for determining an internal characteristic value of at least one transient test model in a transient state of the functional model,

a second step for collecting transient test data by performing a test corresponding to the transient test model,

a third step for applying the steady internal characteristic value to the internal characteristic value of the transient test model to generate transient phenomenon reproduction data, and

a fourth step for correcting the transient phenomenon reproduction data based on an error between the transient phenomenon reproduction data and the transient test data, thereby identifying a transient internal characteristic value.

21. (NEW) The characteristic value identification method as claimed in claim 4, wherein the third process includes: